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/ Ruth Montalvo

Date: 03/22/02

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney's Docket No.:

GK-HIK-2006 / 500572.20049

U.S. Application No.:

International Application No.:

PCT/JP00/06477

International Filing Date:

SEPTEMBER 21, 2000

21 SEPTEMBER 2000

Priority Date Claimed:

SEPTEMBER 24, 1999

24 SEPTEMBER 1999

Title of Invention:

A TWO-SIDE MULTIPLE LAMP TYPE ON-LINE INTERNAL QUALITIES INSPECTION SYSTEM

Applicant(s) for (DO/EO/US):

Atsuhiko NAGAYOSHI and Hiromu MAEDA

Box PCT

Commissioner of Patents

Washington, D. C. 20231

INFORMATION DISCLOSURE STATEMENT

S I R:

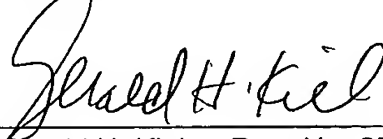
Applicant herewith submits together with the simultaneously filed National Phase application of PCT/JP00/06477, a copy of the International Search Report (PCT/ISA/210) dated November 14, 2000 citing the following references:

	Document Number	Date	Name and/or Country	English Translation
AL	176747/1987	11/10/87	Japan	NO
AM	06-288903 ✓	10/18/94	Japan	NO
AN	07-229840 ✓	08/29/95	Japan	NO
AO	08-201273 ✓	08/09/96	Japan	NO
AP	10-15499 ✓	01/20/98	Japan	NO

Accompanying this Information Disclosure Statement is form PTO-1449 . Copies of the documents are not readily available.

This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted,



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Enclosures:

Search Report (PCT/ISA/210);
PTO-1449;

LIST OF PRIOR ART CITED BY APPLICANT
(Filed on March 22, 2002)

PTO-1449 Equivalent
JG13 Rec'd PCT/PTO 2 2 MAR 2002

Docket No. GK-HIK-2006 / 500572.20049
 Applicant(s): Atsuhiro NAGAYOSHI and Hiromu MAEDA
 Application No. (Int'l Appln No. PCT/JP00/06477 21SEP00) Group:
 Filed: Concurrently herewith - March 22, 2002 Examiner:

U.S. PATENT DOCUMENTS

Exam. Init		Document Number	Date	Name	Class	Sub-Class	Filing Date Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	CLASS	Sub-Class	Translation	
							YES	NO
	AL	176747/1987	11/10/87	Japan				X
	AM	06-288903	10/18/94	Japan				X
	AN	07-229840	08/29/95	Japan				X
	AO	08-201273	08/09/96	Japan				X
	AP	10-15499	01/20/98	Japan				X
	AQ							
	AR							
	AS							

OTHER PRIOR ART *(Including Author, Title, Date, Pertinent Pages, Etc.)*

	AX	
	AY	
	AZ	

Examiner:

Date:

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.